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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/810,419	03/26/2004	Lahir Shaik Adam	TI-36390	TI-36390 8933		
23494	7590 06/22/2005		EXAM	EXAMINER		
TEXAS INSTRUMENTS INCORPORATED P O BOX 655474, M/S 3999			DANG, F	DANG, PHUC T		
DALLAS, TX 75265			ART UNIT	PAPER NUMBER		
,			2818			

DATE MAILED: 06/22/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application	No.	Applicant(s)	
	10/810,419		ADAM ET AL.	
Office Action Summary	Examiner		Art Unit	an
	PHUC T. DA		2818	
The MAILING DATE of this communication appearing for Reply	pears on the c	over sheet with the c	correspondence ad	dress
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, bly within the statuto will apply and will e e, cause the applica	however, may a reply be ting minimum of thirty (30) day xpire SIX (6) MONTHS from tion to become ABANDONE	nely filed s will be considered timely the mailing date of this co D (35 U.S.C. § 133).	
Status				
1) Responsive to communication(s) filed on <u>electrons</u> 2a) This action is FINAL . 2b) This 3) Since this application is in condition for allowated closed in accordance with the practice under the practice under the second	s action is nor ance except fo	r formal matters, pro		e merits is
Disposition of Claims				
4) ☐ Claim(s) 1-25 is/are pending in the application 4a) Of the above claim(s) 18-25 is/are withdray 5) ☐ Claim(s) 10-17 is/are allowed. 6) ☐ Claim(s) 1-8 is/are rejected. 7) ☐ Claim(s) 9 is/are objected to. 8) ☐ Claim(s) are subject to restriction and/o	wn from consi			
Application Papers				
9)☐ The specification is objected to by the Examine 10)☒ The drawing(s) filed on 26 March 2004 is/are: Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)☐ The oath or declaration is objected to by the E	a)⊠ accepte e drawing(s) be ction is required	held in abeyance. Se if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 CF	FR 1.121(d).
Priority under 35 U.S.C. § 119				
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documen 2. Certified copies of the priority documen 3. Copies of the certified copies of the priority application from the International Burea * See the attached detailed Office action for a list	nts have been nts have been ority documen au (PCT Rule	received. received in Applicat ts have been receive 17.2(a)).	ion No ed in this National	Stage
Attachment(s)				
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date	•	Interview Summary Paper No(s)/Mail D Notice of Informal F Other:	ate	D-152)

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DETAILED ACTION

Restriction/election

1. Applicant's election without traverse of Group I (claims 1-17) filed on June 1, 2005, drawn to a method for fabricating a tri-gate semiconductor device and withdrawn Group II (claims 18-25).

Applicants have the right to file a divisional application covering the subject matter of the non-elected claims.

Specification

2. The specification has been checked to the extent necessary to determine the presence of all possible minor errors. However, the applicant's cooperation is requested in correcting any errors of which applicant may become aware in the specification.

Claim Rejections - 35 USC § 102

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(f) or (g) prior art under 35 U.S.C. 103(a).

3. Claims 1, 4-6, and 8 are rejected under 35 U.S.C. 102 (b) as being anticipated by Chang et al., hereinafter "Chang" (U.S. Patent No. 6,204,159 B1).

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Regarding claims 1, Chang discloses a method for forming a NAND gate flash memory device comprising:

forming a high voltage gate dielectric layer (48, Fig. 7) over a semiconductor substrate (30, Fig. 7);

implanting a low dose of nitrogen (col. 8, lines 34-35) into the semiconductor substrate (30, Fig. 7) in a low voltage core region (34, Fig. 8); and

forming a low voltage core gate dielectric layer (58, Fig. 7) over the low voltage core region (34, Fig. 8), including forming an intermediate core gate dielectric layer (40, Figs. 6-11) over an intermediate core region (46, Fig. 11).

Regarding claims 4-5, Chang discloses the thickness of the gate dielectric layers are applied in the process [col. 5, lines 49-52 and col. 8, lines 55+].

Regarding claim 6, Chang discloses forming the low voltage core gate dielectric layer (58, Fig. 7) and the intermediate core dielectric layer (40, Fig. 7) is conducted in the presence of an environment of nitrogen [col. 8, lines 27-38].

Regarding claim 8, Chang discloses forming a first gate over the high voltage gate dielectric layer, forming a second gate over the low voltage core gate dielectric layer and forming a third gate over the intermediate core dielectric layer [Fig. 12].

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior

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art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

4. Claims 2-3 and 7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chang in view of An et al., hereinafter "An" (U.S. Patent No. 6,165,849).

Chang discloses all the features of the claimed invention as discussed above, but does not disclose the implanting of the low dose ranges of nitrogen into the substrate.

An, however, discloses the implanting of the low dose ranges of nitrogen into the substrate [col. 3, lines 18-29].

It would have been obvious to one having ordinary skilled in the art at the time the invention was made to modify the above discussed teaching of Chang as taught by An for a purpose of improving the reliability in the processing.

Allowable Subject Matter

5. Claims 10-17 would be allowed.

The following is a statement of reason for the indication of allowable subject matter:

Claims 10-17 are considered allowable since the prior art of record and the considered pertinent to the applicant's disclosure does not teach or suggest the claimed invention having a step of forming interconnects extending through dielectric layers located over first, second, and third transistor gates to interconnect the first, second and third transistor gates to form an operative tri-gate integrated circuit as cited in claim 10.

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Claim 9 is objected to as being dependent upon a rejected base claim, but would be

allowable if rewritten in independent form including all of the limitations of the base claim and

any intervening claim.

None of the prior art made of record does not disclose a step of forming the second gate

includes forming the second gate such that a concentration of nitrogen within the second gate is

substantially uniform through the second gate.

Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner

should be directed to Phuc T. Dang whose telephone number is (571) 272-1776. The examiner

can normally be reached on 8:00 am-5:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, 7.

David C. Nelms can be reached on (571) 272-1787. The fax phone numbers for the organization

where this application or proceeding is assigned are 703-872-9306 for regular communications

and After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is 703-308-0956.

Langgohur

Phuc T. Dang

Primary Examiner

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